

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	1.996	1.58	2.5±1	3.5	2.24	<5	0.69393	3.00	YES
	2.441	3.4	2.19	2.5±1	3.5	2.24	<5	0.69954	3.00	YES
	2.480	1.635	1.46	2±1	3	2.00	<5	0.62843	3.00	YES
$\pi/4$ -DQPSK	2.402	2.542	1.80	3.5±1	4.5	2.82	<5	0.87361	3.00	YES
	2.441	4.327	2.71	3.5±1	4.5	2.82	<5	0.88067	3.00	YES
	2.480	2.364	1.72	3±1	4	2.51	<5	0.79114	3.00	YES
8-DQPSK	2.402	2.749	1.88	3.5±1	4.5	2.82	<5	0.87361	3.00	YES
	2.441	4.239	2.65	3.5±1	4.5	2.82	<5	0.88067	3.00	YES
	2.480	2.377	1.73	3±1	4	2.51	<5	0.79114	3.00	YES
BLE	2.402	1.127	1.30	2±1	3	2.00	<5	0.61847	3.00	YES
	2.440	3.009	2.00	2.5±1	3.5	2.24	<5	0.69940	3.00	YES
	2.480	1.241	1.33	2±1	3	2.00	<5	0.62843	3.00	YES

Conclusion:

For the max result : $0.88067 \leq 3.0$ for 1g SAR, SAR is not required.



Signature:

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